

**PATENT** KIK01 P322

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Art Unit

: 2863

Examiner

: Xiuquin Sun

**Applicant** 

: Kenichiro Kobayashi

Serial No.

: 09/838,905

Filed

: April 20, 2001

Confirmation No.: 1673

For

: METHOD AND APPARATUS TO MEASURE AMOUNT OF

METHOD AND APPARATUS TO MEASURE AMOUNT OF
MOVEMENT USING GRANULAR SPECK PATTERN GENERATED
BY REFLECTING LASER BEAM

oner for Patents
0231

AMENDMENT

Assistant Commissioner for Patents Washington, DC 20231

Dear Sir:

Responsive to the Office Action mailed June 4, 2002, please amend the above-identified application as follows. A marked-up copy of the claims being amended follows in Appendix A.

## In the Claims

## Please amend claims 1, 2, 6, 7, 8, and 13 as follows:

A lensless method for measuring the amount which an object to be measured has 1. moved in a plane and back-and-forth using a granular speck pattern generated by a reflecting laser beam in non-contact fashion comprising steps of:

irradiating an object to be measured with a laser beam;

directly detecting the granular speck pattern generated by the reflecting laser beam by a detector and using the detected speck pattern as an index;

moving the object toward or away from the detector;